

# Description

The AON7426 uses advanced trench technology

to provide excellent  $R_{DS(ON)}$ , low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

#### **General Features**

V<sub>DS</sub> = 30V I<sub>D</sub> =80 A

 $R_{DS(ON)} < 6 \text{ m}\Omega$  @V<sub>GS</sub>=10V

# Application

Battery protection

Load switch

Uninterruptible power supply

#### Package Marking and Ordering Information

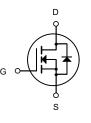
Product ID	Pack	Brand	Qty(PCS)
AON7426	DFN3X3-8L	HXY MOSFET	5000

### Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	ce Voltage 30	
VGS	Gate-Source Voltage	±20	V
I₀@Tc=25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	80	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	50	A
IDM	Pulsed Drain Current <sup>2</sup>	162	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	144.7	mJ
IAS	Avalanche Current	53.8	А
P₀@Tc=25°C	Total Power Dissipation <sup>4</sup>	62.5	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-ambient <sup>1</sup>	62	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	2.4 °C/W	







N-Channel MOSFET



Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS} / \triangle T_J$	BVDSS Temperature Coefficient	Reference to 25°C,I <sub>D</sub> =1mA		0.0213		V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =30A		4.7	6	mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		5.9	8	
V <sub>GS(th)</sub>	Gate Threshold Voltage		1.0	1.5	2.5	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250$ uA		-5.73		mV/°C
	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	- uA
I <sub>DSS</sub>		$V_{DS}$ =24V , $V_{GS}$ =0V , $T_J$ =55°C			5	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =30A		26.5		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.4	2.8	Ω
Qg	Total Gate Charge (4.5V)			31.6		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		8.6		nC
$Q_{gd}$	Gate-Drain Charge			11.7		
T <sub>d(on)</sub>	Turn-On Delay Time			9		
Tr	Rise Time	$V_{DD}$ =15V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		19		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =15A		58		ns
T <sub>f</sub>	Fall Time			15.2		
C <sub>iss</sub>	Input Capacitance			3075	4000	
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		400	530	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			315		
ls	Continuous Source Current <sup>1,5</sup>				80	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,5</sup>	──V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			162	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=30A , dl/dt=100A/µs ,		18		nS
Qrr	Reverse Recovery Charge			8		nC

### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Note :

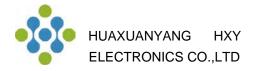
1. The data tested by surface mounted on a 1 inch $^2$  FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

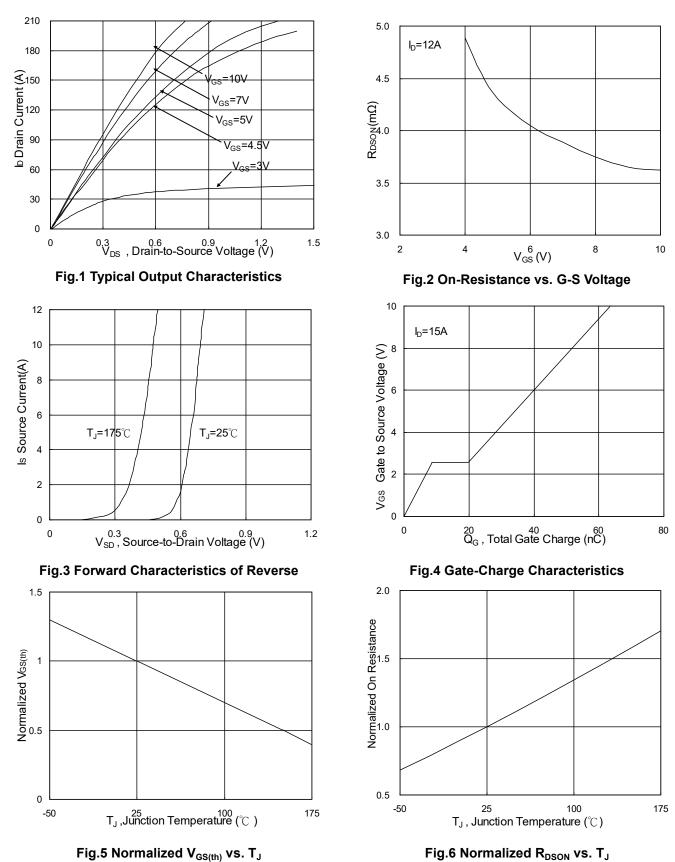
3.The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}\text{=}25\text{V}, V_{\text{GS}}\text{=}10\text{V}, \text{L=}0.1\text{mH}, I_{\text{AS}}\text{=}53.8\text{A}$ 

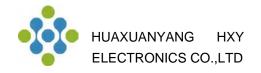
4. The power dissipation is limited by 175°C junction temperature

5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **Typical Characteristics**





# AON7426 N-Channel Enhancement Mode MOSFET

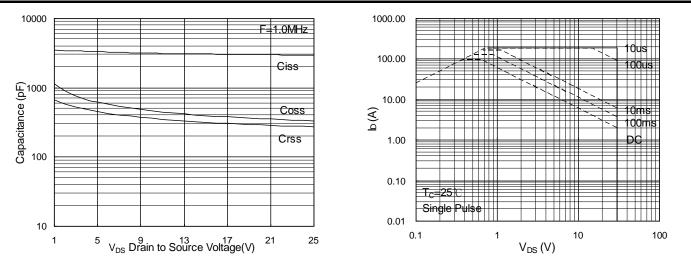




Fig.8 Safe Operating Area

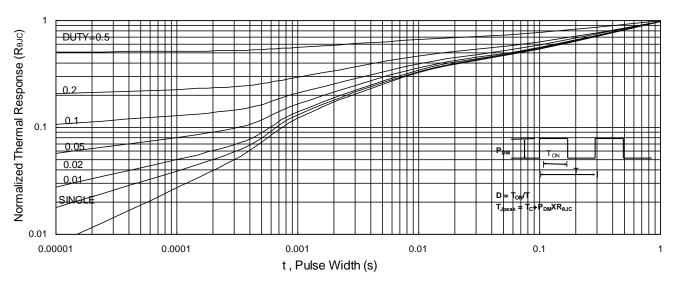


Fig.9 Normalized Maximum Transient Thermal Impedance

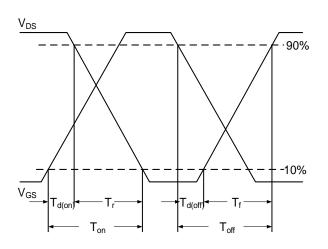
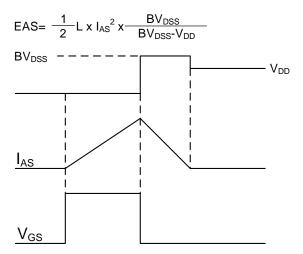


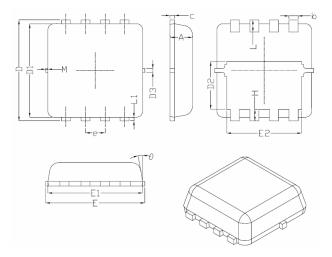
Fig.10 Switching Time Waveform



# Fig.11 Unclamped Inductive Switching Waveform



# DFN3X3-8L Package Information



Symbol	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
e	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
М	*	*	0.15	
θ		10 <sup>°</sup>	12 <sup>°</sup>	



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